Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/917,253	PHAM ET AL.	
Examiner	Art Unit	
I ena Najarjan	3626	

	SEAR	CHED	
Class	Subclass	Date	Examiner
705	2 3	11/22/2005	LN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARC		
	DATE	EXMR
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	11/18/2005	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	11/21/2005	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	11/22/2005	LN